

Date: February 1, 2005

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(REV. 05/03)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MAIT-003AX (Formerly 301505.3002-103)		APPLICATION NO. 10/823,389	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				APPLICANT: Christopher M. Fang-Yen, <i>et al.</i>			
FILING DATE April 13, 2004				TC ART UNIT 2877			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION/ ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE	
/PC/	US 3,970,389	20 July 1976	Mendrin, <i>et al.</i>	357	106		
	US 4,702,603	27 Oct 1987	Augustyn	356	351		
	US 4,756,611	12 Jul 1988	Yonekubo, <i>et al.</i>	350	509		
	US 4,938,584	3 July 1990	Suematsu, <i>et al.</i>	351	211		
	US 5,018,862	28 May 1991	Aiello	356	358		
	US 5,124,927	23 Jun 1992	Hopewell, <i>et al.</i>	364	468		
	US 5,153,669	6 Oct 1992	DeGroot	356	349		
	US 5,263,776	23 Nov 1993	Abraham, <i>et al.</i>	374	161		
	US 5,349,440	20 Sep 1994	DeGroot	356	349		
	US 5,371,587	6 Dec 1994	DeGroot, <i>et al.</i>	356	349		
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	US 5,446,540	29 Aug 1995	Lin	356	345		
	US 5,450,501	12 Sep 1995	Smid	382	260		
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EXAMINER

/Patrick Connolly/ (05/14/2007)

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

****The art was cited in PCT International Search Report mailed July 4, 2003 in International Application No. PCT/US02/40440 filed December 12, 2002.**